

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LAU ET AL.	
		Examiner LaShanya R Nash	Art Unit 2153	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0033430	02-2003	Lau et al.	709/245
	B	US-2002/0144156	10-2002	Copeland, John A. III	713/201
	C	US-6,735,190	05-2004	Chuah et al.	370/352
	D	US-6,304,914	10-2001	Deo et al.	709/247
	E	US-6,321,264	11-2001	Fletcher et al.	709/224
	F	US-6,363,477	03-2002	Fletcher et al.	713/151
	G	US-6,286,052	09-2001	McCloghrie et al.	709/238
	H	US-2001/0021176	09-2001	Mimura et al.	370/235
	I	US-6,065,064	05-2000	Satoh et al.	709/249
	J	US-6,625,662	09-2003	Satoh et al.	709/250
	K	US-2001/0050903	12-2001	Vanlint, Paul	370/252
	L	US-6,466,985	10-2002	Goyal et al.	709/238
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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